

Fraunhofer Institute for Integrated Circuits IIS
Division Engineering of Adaptive Systems EAS

Chiplets for future automotive application

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Introduction - Use Cases

- **Data center**

- High speed data processing
- Contains:
 - **Different processing unit**
 - **Memory**
 - **Interfacing**
- High speed data processing
 - **E.g. 3/5/7 nm for digital processing**
 - **E.g. 12 nm for IO interfaces**
- Production volume: mid size volume
- Budget for exploration: available

Introduction - Use Cases

- **Measurement equipment**

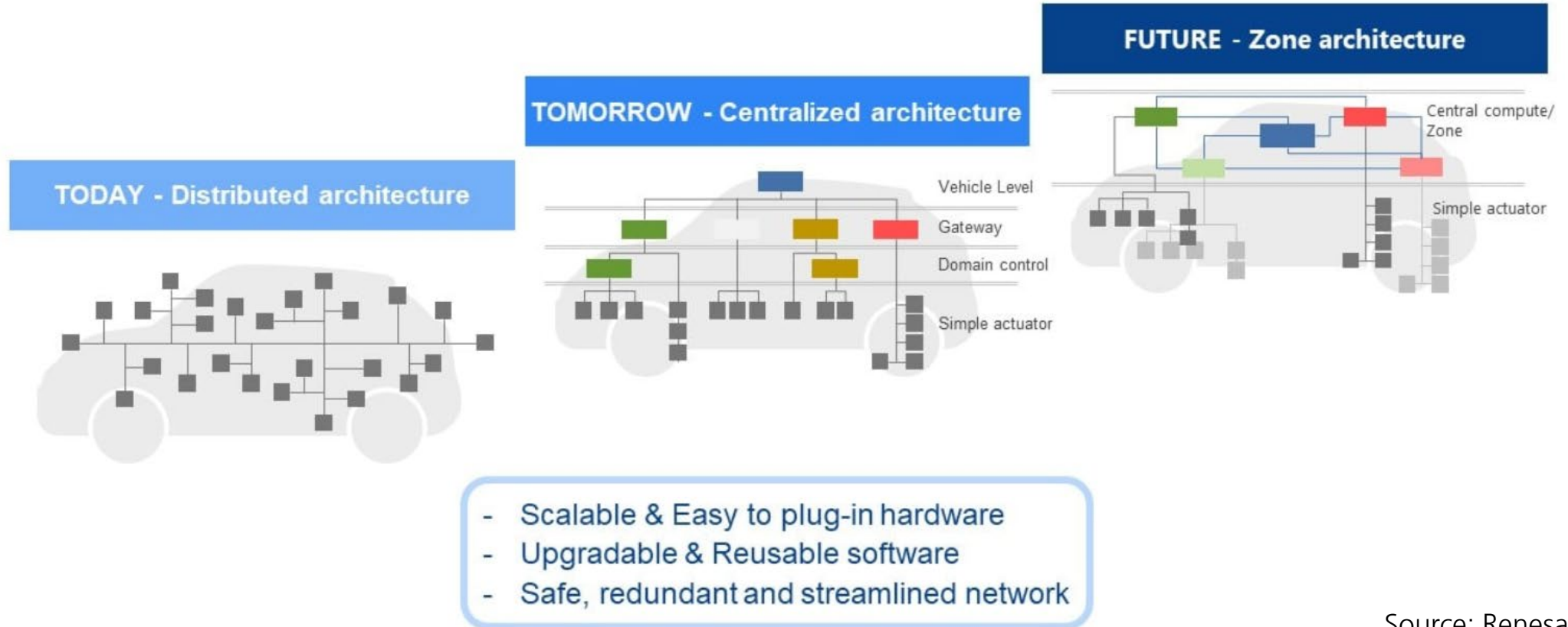
- High speed data acquisition in the range of Gbit/s or Tbit/s from small number of channels
- Contains:
 - **Analog-to-digital Converter (ADC)**
 - **Digital pre-processing eFPGA (flexible, ...)**
 - **Digital processing DSP (FFT, ...)**
- High speed data acquisition needs heterogenous integration approaches with highly specific technologies
 - **E.g. SiGe for data acquisition**
 - **E.g. 5/7 nm for digital processing**
- Production volume: very small volume
- Budget for exploration: not available

Introduction - Use Cases

● Automotive

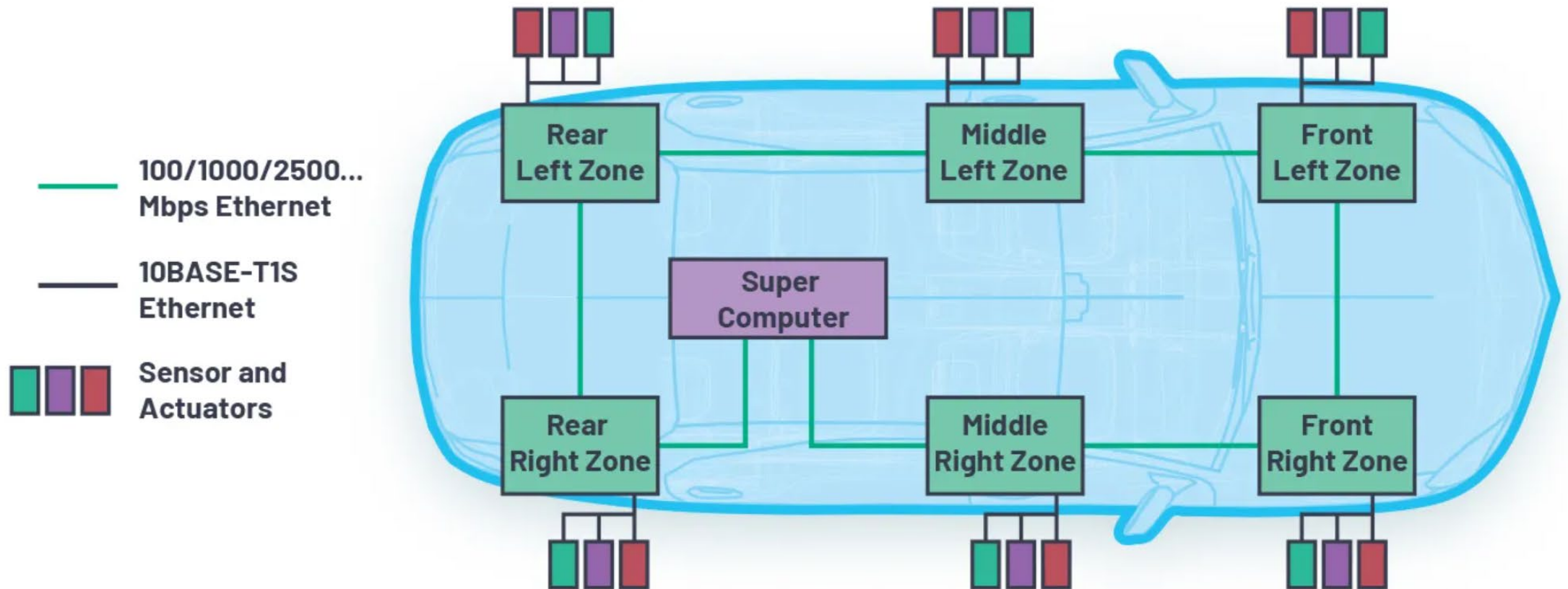
- High speed data acquisition in the range of Gbit/s or Tbit/s from a large number of channels (Lidar, Radar, Kamera, ...)
- Contains:
 - Sensors: Lidar, Radar, Kamera
 - Digital pre-processing eFPGA (flexible, ...)
 - Digital processing DSP
 - Digital processing CPU
- Automotive needs a building block for flexible configurations
- Production volume: low/mid size volume
- Budget for exploration: available

MEGATREND – E/E ARCHITECTURE TRANSFORMATION



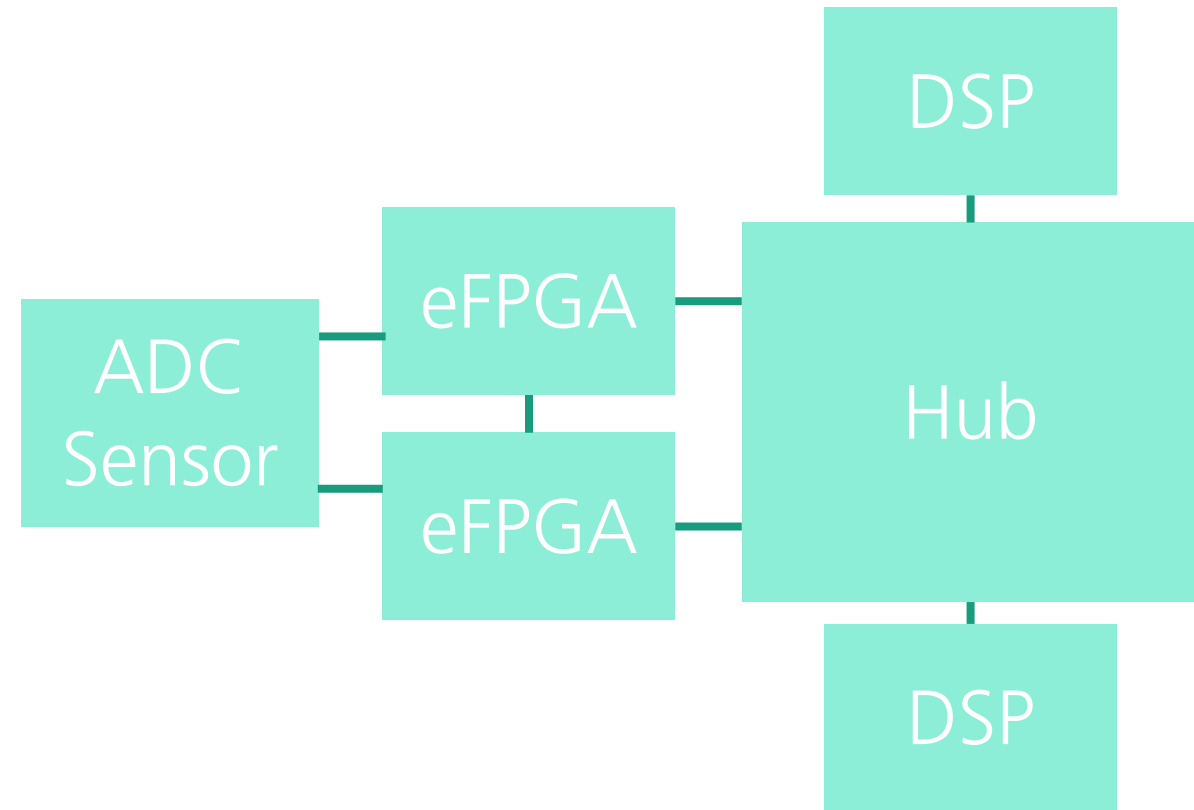
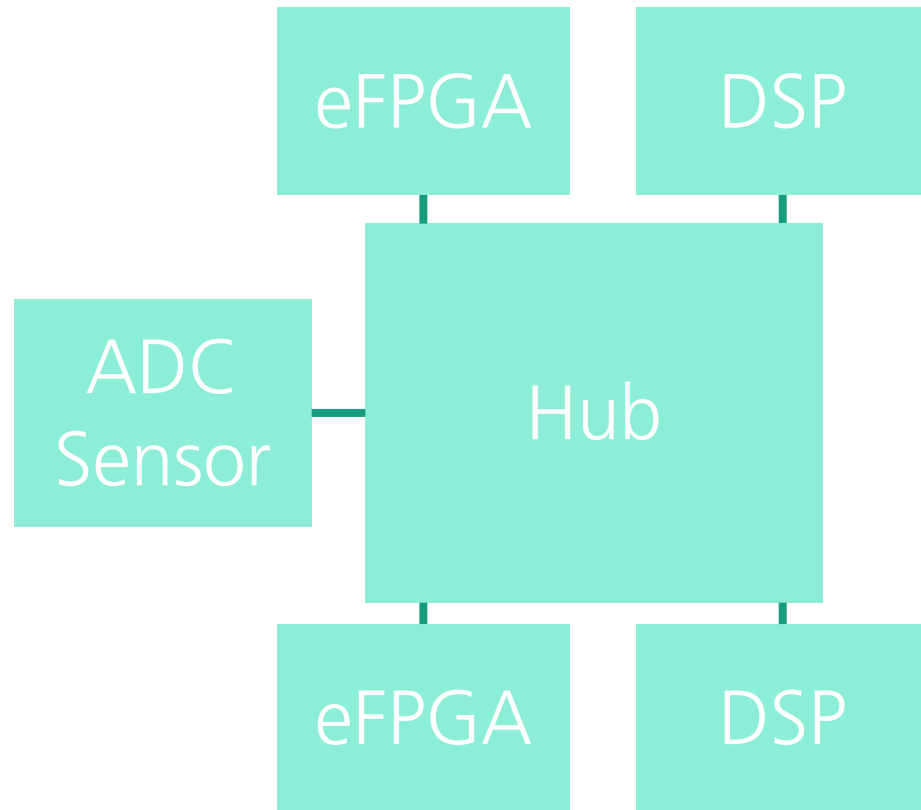
Source: Renesas

EE-architectures

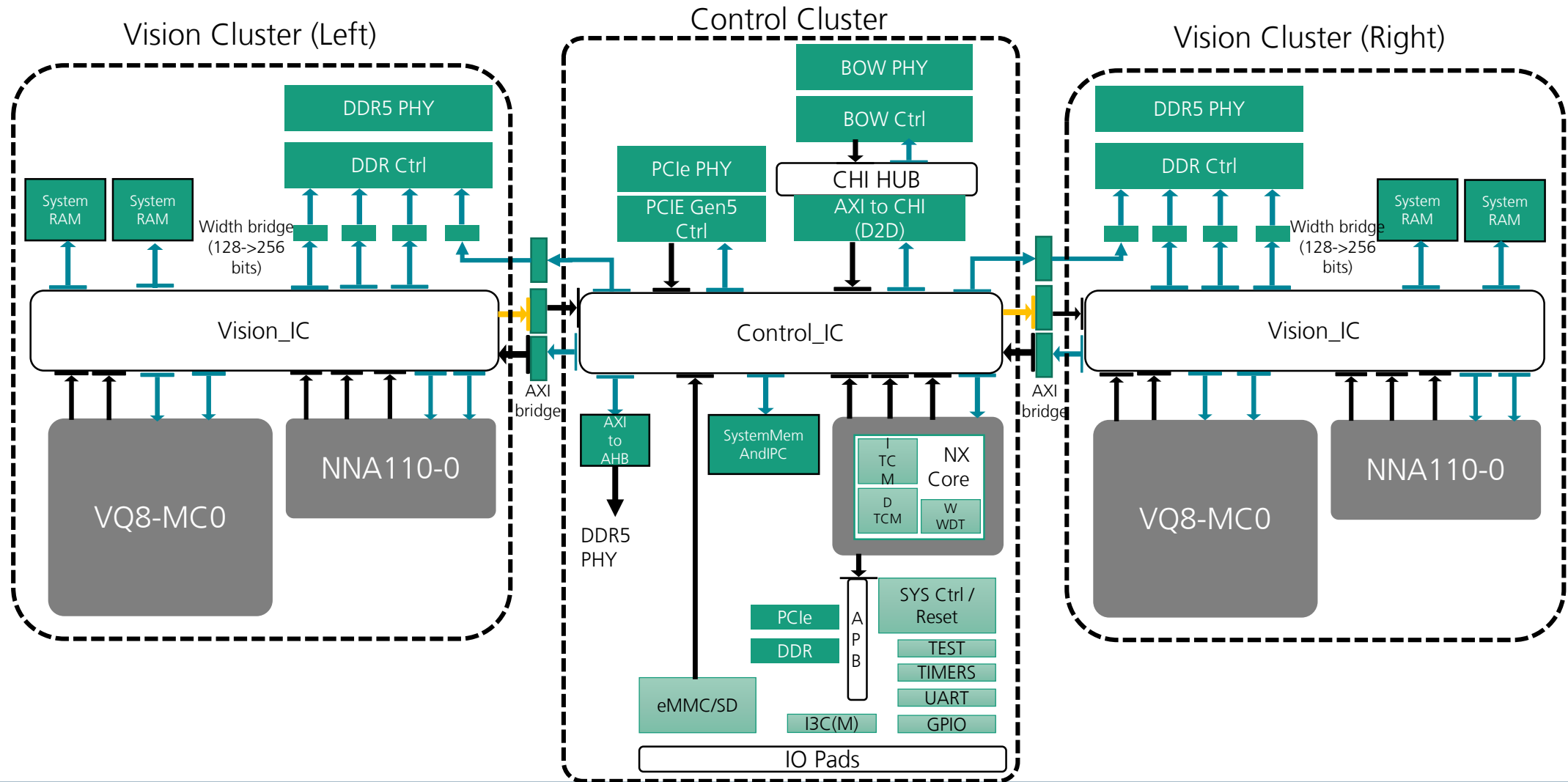


Source: Analog Devices

Architectures for Zone controller and HPC



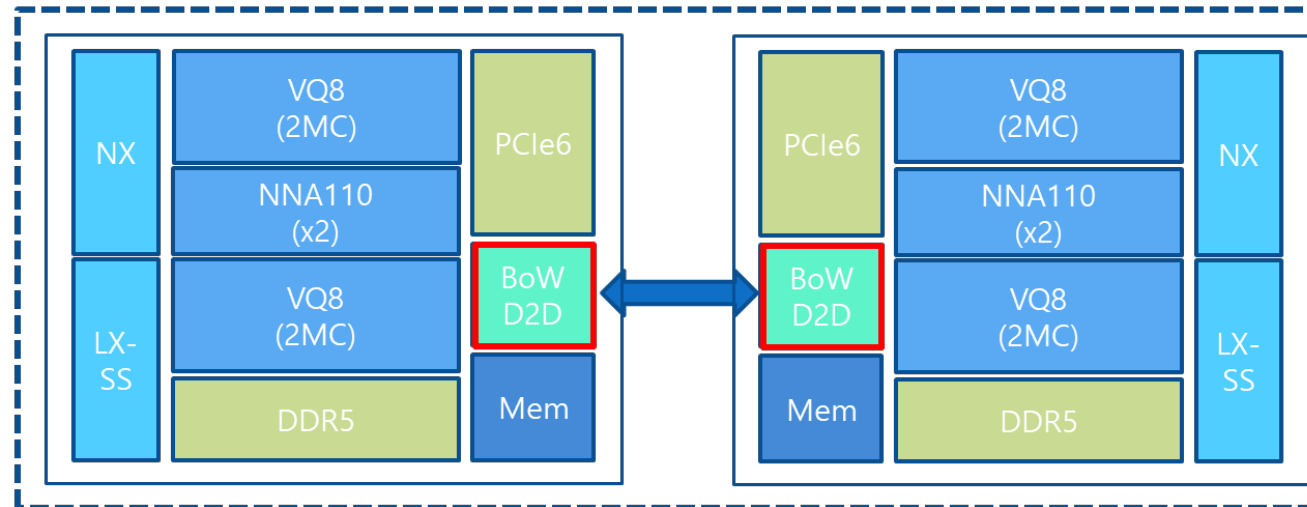
Test/reference system



Test/reference system

- ⊕ Samsung Advanced SF5A Process
- ⊕ Cadence NNA110 & Q8 Vision Core
- ⊕ IO/Memory Core: PCIe6 and DDR5
- ⊕ System Memory: Xenergetic
- ⊕ Chiplet I/F: BoW D2D
- ⊕ Chiplet – leverage multiple dies in the same package
- ⊕ Leverage chiplet and IP reuse
- ⊕ Highlight Cadence Multi Die tools
- ⊕ Utilize Samsung Multi Die Packaging

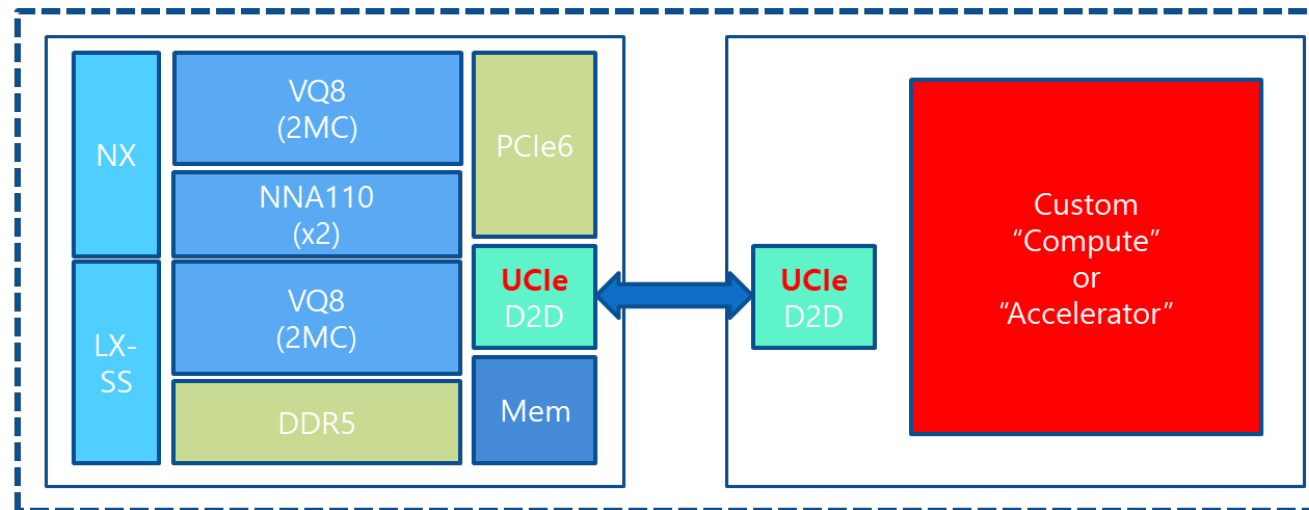
Chiplet SoC



Test/reference system

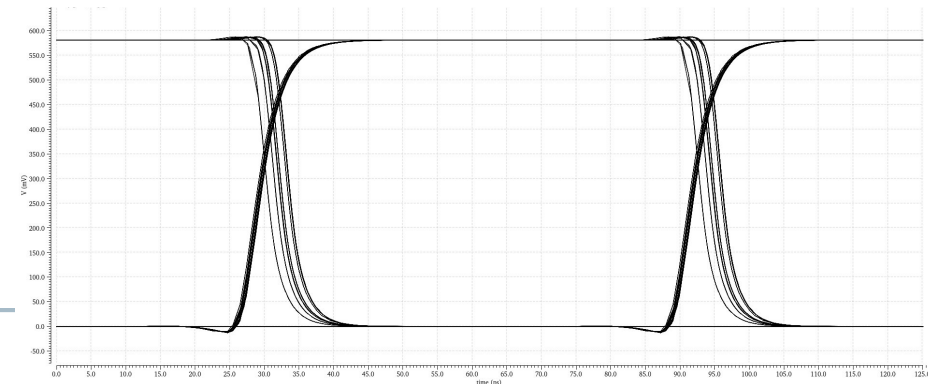
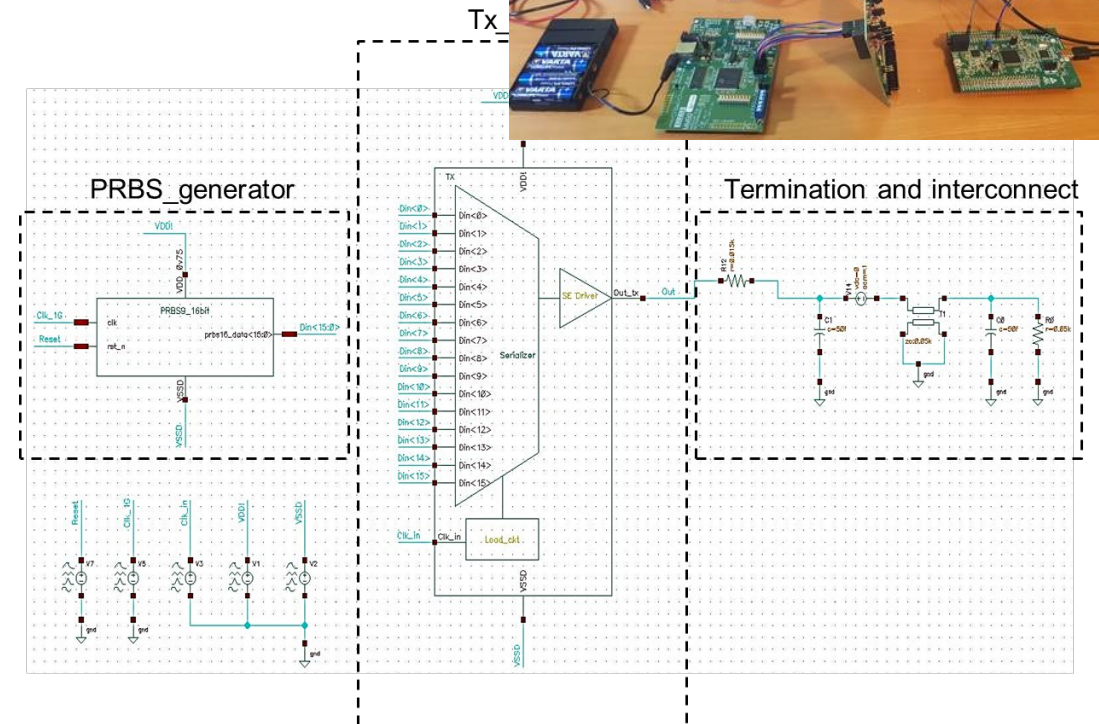
- ⊕ A Samsung 5nm IO Hub Platform
- ⊕ Proven architecture and interoperability
- ⊕ Leverage SW built on Tensilica DSP
- ⊕ Ability to change/customize blocks
- ⊕ D2D: **BoW → UCle**
- ⊕ PCIe: **PCIe6 → PCIe5 or more lanes**
- ⊕ DDR: **5600 → 6400/7200/8400 or LPDDR/GDDR/HBM**
- ⊕ System Memory: **change size or config.**
- ⊕ Cores: **select from AI/ML to Vision to Audio**

Chiplet SoC



Die to Die Interface (BoW, UCle)

- TX single operates at a clock frequency of 16 GHz and consists of three main blocks:
 - Parallel-in-Serial-out (PISO)** to serialize the incoming input data.
 - Loading circuit** which generates the control signal for PISO.
 - Single-ended (SE) Driver** operates at a data frequency of 16 Gbps.
- A **PRBS_generator** generates a 16 bits of PRBS-9 input signal. It operates at 1GHz.
- A **Termination resistance** of 15Ω is connected in series to the SE Driver.
- VDD = 0.75 V
- Unit Interval (UI) = $1/\text{Data rate} = 62.5 \text{ ps}$



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